ON Semiconductor

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MOSFET – Power, Single

N-Channel

60 V, 6.8 m Ω , **71 A**

NVTYS006N06CL

Features

- Small Footprint (3.3 x 3.3 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	60	٧
Gate-to-Source Voltage	Э		V _{GS}	±20	V
Continuous Drain	Steady	T _C = 25°C	I _D	71	Α
Current R _{θJC} (Notes 1, 2, 3, 4)		T _C = 100°C		50	
Power Dissipation	State	T _C = 25°C	P_{D}	61	W
R _{θJC} (Notes 1, 2, 3)		T _C = 100°C		31	
Continuous Drain		T _A = 25°C	I _D	16	Α
Current R _{θJA} (Notes 1, 3, 4)	Steady State	T _A = 100°C		11	
Power Dissipation		T _A = 25°C	P_{D}	3.2	W
R _{θJA} (Notes 1, 3)		T _A = 100°C		1.6	
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I _{DM}	322	Α
Operating Junction and Storage Temperature Range Source Current (Body Diode) Single Pulse Drain-to-Source Avalanche Energy (I _{L(pk)} = 3.6 A) Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			T _J , T _{stg}	-55 to +175	°C
			I _S	51	Α
			E _{AS}	115	mJ
			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State (Note 3)	$R_{\theta JC}$	2.4	°C/W
Junction-to-Ambient - Steady State (Note 3)	$R_{\theta JA}$	47	

- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- Psi (Ψ) is used as required per JESD51–12 for packages in which substantially less than 100% of the heat flows to single case surface.
- 3. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- Continuous DC current rating. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

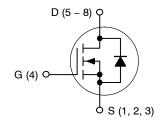


ON Semiconductor®

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V _{(BR)DSS}	/(BR)DSS R _{DS(on)} MAX		
60 V	6.8 mΩ @ 10 V	71 A	
60 V	10 mΩ @ 4.5 V	/	

N-Channel





LFPAK8 3.3x3.3 CASE 760AD

MARKING DIAGRAM

006N 06CL AWLYW

006N06CL = Specific Device Code

A = Assembly Location

WL = Wafer Lot Y = Year WW = Work Week

ORDERING INFORMATION

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
OFF CHARACTERISTICS								
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		60			V	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				28		mV/°C	
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V.	T _J = 25°C			10	μΑ	
		$V_{GS} = 0 V$, $V_{DS} = 60 V$	T _J = 125°C			250	1	
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _G	_S = 20 V			100	nA	
ON CHARACTERISTICS (Note 5)					-			
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{DS}$) = 53 μΑ	1.2		2.0	V	
Threshold Temperature Coefficient	V _{GS(TH)} /T _J				-4.8		mV/°C	
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 35 A		5.8	6.8	mΩ	
		V _{GS} = 4.5 V	I _D = 35 A		8.1	10	1	
Forward Transconductance	9 _{FS}	V _{DS} = 5 V, I _D	₎ = 35 A		67		S	
CHARGES AND CAPACITANCES							•	
Input Capacitance	C _{ISS}				1330		pF	
Output Capacitance	Coss	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 25 V			740			
Reverse Transfer Capacitance	C _{RSS}				11			
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 4.5 V, V _{DS} = 48 V; I _D = 35 A			8		nC	
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 48 V; I _D = 35 A			19		nC	
Threshold Gate Charge	Q _{G(TH)}	V _{GS} = 10 V, V _{DS} = 48 V; I _D = 35 A			2		nC	
Gate-to-Source Charge	Q _{GS}				4.3		1	
Gate-to-Drain Charge	Q_{GD}				1.6		1	
Plateau Voltage	V_{GP}				3.1		V	
SWITCHING CHARACTERISTICS (Note 6	3)				•	•	•	
Turn-On Delay Time	t _{d(ON)}				13.6		ns	
Rise Time	t _r	V _G s = 4.5 V. V _I	ne = 48 V.		7.7		1 !	
Turn-Off Delay Time	t _{d(OFF)}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 48 \text{ V},$ $I_{D} = 35 \text{ A}, R_{G} = 2.5 \Omega$			16.3		1 '	
Fall Time	t _f				6.1			
DRAIN-SOURCE DIODE CHARACTERIS	TICS							
Forward Diode Voltage	V_{SD}	V _{GS} = 0 V,	T _J = 25°C		0.9	1.2	V	
		$I_S = 35 A$	T _J = 125°C		0.8			
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } dI_{S}/d_{t} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 35 \text{ A}$			37		ns	
Charge Time	ta				18		†	
Discharge Time	t _b				19		1	
Reverse Recovery Charge	Q _{RR}				22		nC	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 5. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$. 6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

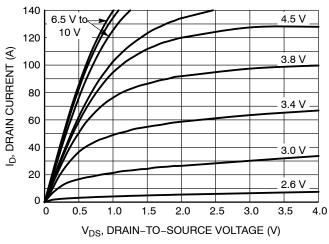


Figure 1. On-Region Characteristics

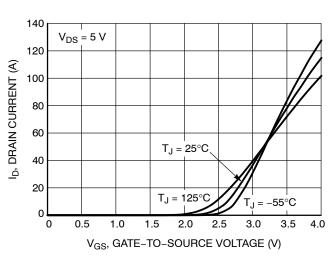


Figure 2. Transfer Characteristics

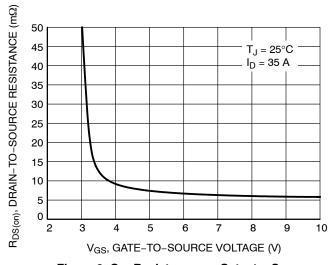


Figure 3. On-Resistance vs. Gate-to-Source Voltage

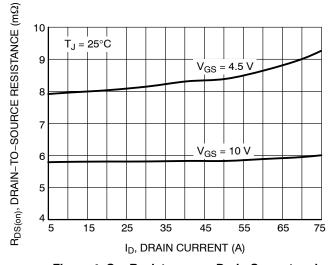


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

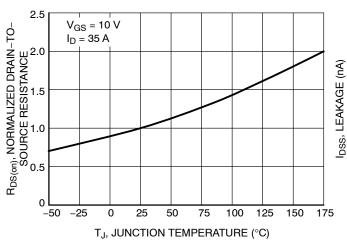


Figure 5. On–Resistance Variation with Temperature

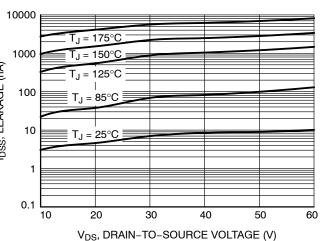


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

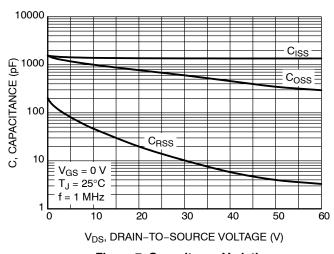


Figure 7. Capacitance Variation

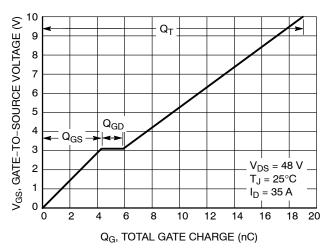


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

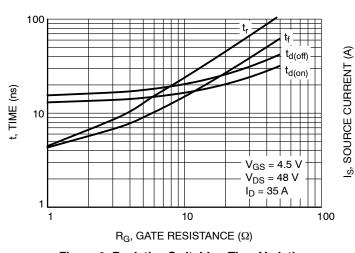


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

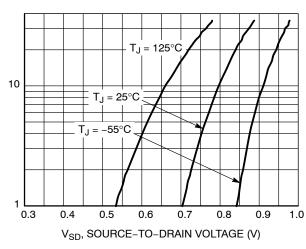


Figure 10. Diode Forward Voltage vs. Current

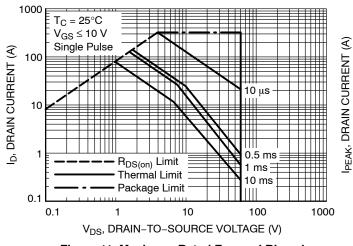


Figure 11. Maximum Rated Forward Biased Safe Operating Area

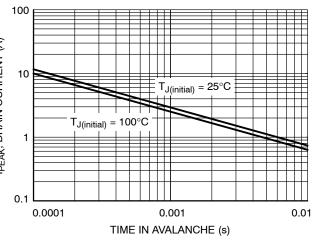


Figure 12. Maximum Drain Current vs. Time in Avalanche

TYPICAL CHARACTERISTICS

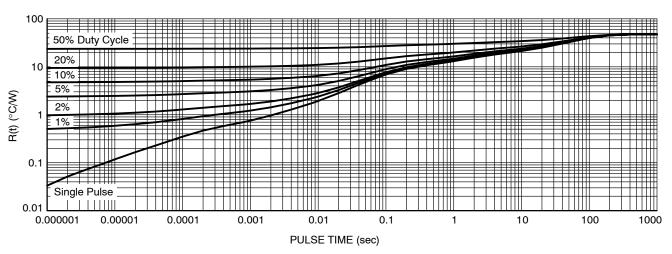


Figure 13. Thermal Characteristics

DEVICE ORDERING INFORMATION

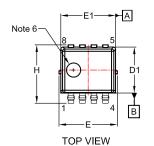
Device		Marking Package		Shipping [†]
	NVTYS006N06CLTWG	006N 06CL	LFPAK33	3000 / Tape & Reel

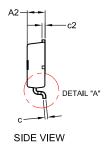
[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

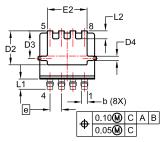
PACKAGE DIMENSIONS

LFPAK8 3.3x3.3, 0.65P

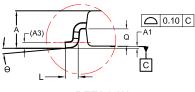
CASE 760AD ISSUE E



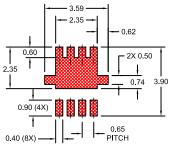












LAND PATTERN RECOMMENDATION

*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- 3. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS OR BURRS SHALL NOT EXCEED 0,150mm PER SIDE,
- 4. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.
- 6. OPTIONAL MOLD FEATURE.

DIM	MILLIMETERS			
Diw	MIN.	NOM.	MAX.	
Α	0.95	1.05	1.15	
A1	0.00	0.05	0.10	
A2	0.95	1.00	1.05	
A3		0.15 REI	F	
b	0.27	0.32	0.37	
С	0.12	0.17	0.22	
c2	0.12	0.17	0.22	
D1	2.50	2.60	2.70	
D2	1.82	1.92	2.02	
D3	1.46	1.56	1.66	
D4	0.20	0.25	0.30	
Е	3.20	3.30	3.40	
E1	3.00	3.10	3.20	
E2	2.15	2.25	2.35	
е	0.65 BSC			
I	3.20	3.30	3.40	
L	0.25	0.37	0.50	
L1	0.48	0.58	0.68	
L2	0.35	0.45	0.55	
Q	0.45	0.50	0.55	
θ	0°	4°	8°	
0	U	-		

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